



5/27/03  
#3/Amgt  
entered  
in part

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re U.S. Patent Application of: ) Attorney Docket: 4425-168  
 )  
Yen-Ting Lu ) Group Art Unit: 1756  
 )  
Serial No.: 09/919,868 ) Examiner: C. G. Young  
 )  
Filed: August 2, 2001 )

For: METHOD FOR REDUCING LINE EDGE  
ROUGHNESS OF PHOTORESIST

RECEIVED  
MAY 27 2003

TC 1700

AMENDMENT

Honorable Commissioner for Patents  
Washington, D.C. 20231

Sir:

This is in response to the Office Action of February 21, 2003, in connection with the above-identified application.